Advance Information Low-Voltage CMOS Unbuffered Hex Inverter

With 5 V-Tolerant Inputs

The MC74LCXU04 is a high performance unbuffered hex inverter operating from a 2.3 to 3.6 V supply. High impedance TTL compatible inputs significantly reduce current loading to input drivers while TTL compatible outputs offer improved switching noise performance. A V_I specification of 5.5 V allows MC74LCXU04 inputs to be safely driven from 5 V devices.

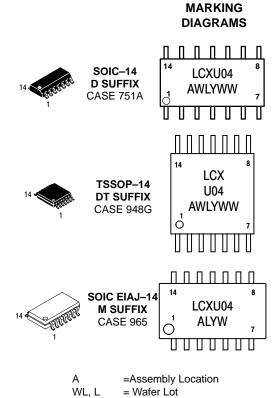
Current drive capability is 24 mA at the outputs.

- Designed for 2.3 to 3.6 V V_{CC} Operation
- 5 V Tolerant Inputs Interface Capability With 5 V TTL Logic
- LVTTL Compatible
- LVCMOS Compatible
- 24 mA Balanced Output Sink and Source Capability
- Near Zero Static Supply Current (10 µA) Substantially Reduces System Power Requirements
- Latchup Performance Exceeds 500 mA
- ESD Performance: Human Body Model >2000 V; Machine Model >200 V



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ORDERING INFORMATION

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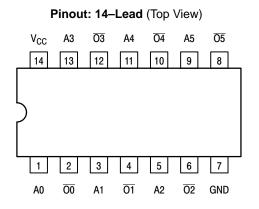
= Work Week

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WW, W

Device	Package	Shipping
MC74LCXU04D	SOIC-14	55 Units/Rail
MC74LCXU04DR2	SOIC-14	2500 Units/Reel
MC74LCXU04DT	TSSOP-14	96 Units/Rail
MC74LCXU04DTR2	TSSOP-14	2500 Units/Reel
MC74LCXU04M	SOIC EIAJ–14	50 Units/Rail
MC74LCXU04MEL	SOIC EIAJ–14	2000 Units/Reel

This document contains information on a new product. Specifications and information herein are subject to change without notice.



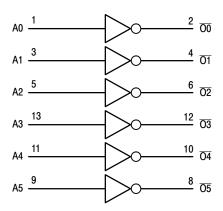
PIN NAMES

Pins	Function
An	Data Inputs
On	Outputs

FUNCTION TABLE

An	On
L	H
H	L

LOGIC DIAGRAM



ABSOLUTE MAXIMUM RATINGS*

Symbol	Parameter	Value	Condition	Unit
V _{CC}	DC Supply Voltage	-0.5 to +7.0		V
VI	DC Input Voltage	$-0.5 \le V_1 \le +7.0$		V
Vo	DC Output Voltage	$-0.5 \leq V_O \leq V_{CC} + 0.5$	Note 1.	V
I _{IK}	DC Input Diode Current	-50	V _I < GND	mA
I _{OK}	DC Output Diode Current	-50	V _O < GND	mA
		+50	$V_{O} > V_{CC}$	mA
I _O	DC Output Source/Sink Current	±50		mA
I _{CC}	DC Supply Current Per Supply Pin	±100		mA
I _{GND}	DC Ground Current Per Ground Pin	±100		mA
T _{STG}	Storage Temperature Range	-65 to +150		°C

* Absolute maximum continuous ratings are those values beyond which damage to the device may occur. Exposure to these conditions or conditions beyond those indicated may adversely affect device reliability. Functional operation under absolute-maximum-rated conditions is not implied. 1. Output in HIGH or LOW State. I_O absolute maximum rating must be observed.

RECOMMENDED OPERATING CONDITIONS

Symbol	Paramete	er	Min	Тур	Max	Unit
V _{CC}	Supply Voltage	Operating Data Retention Only	2.0 1.5	2.3 to 3.3	3.6 3.6	V
VI	Input Voltage		0		5.5	V
V _O	Output Voltage	(HIGH or LOW State)	0		V _{CC}	V
I _{OH}	HIGH Level Output Current	$V_{CC} = 3.0V - 3.6V \\ V_{CC} = 2.7V - 3.0V \\ V_{CC} = 2.3V - 2.7V$			- 24 - 12 - 8	mA
I _{OL}	LOW Level Output Current	$V_{CC} = 3.0V - 3.6V$ $V_{CC} = 2.7V - 3.0V$ $V_{CC} = 2.3V - 2.7V$			+ 24 + 12 + 8	mA
T _A	Operating Free–Air Temperature		-40		+85	°C
$\Delta t / \Delta V$	Input Transition Rise or Fall Rate, $V_{CC} = 3.0V$	V _{IN} from 0.8V to 2.0V,	0		10	ns/V

DC ELECTRICAL CHARACTERISTICS

			T _A = -40°C		
Symbol	Characteristic	Condition	Min	Max	Unit
V _{IH}	HIGH Level Input Voltage (Note 2.)	$V_{CC} = 2.3V$ $V_{CC} = 2.7V$ $V_{CC} = 3.0V$ $V_{CC} = 3.6V$	1.8 1.9 2.3 2.8		V
V _{IL}	LOW Level Input Voltage (Note 2.)	$V_{CC} = 2.3V$ $V_{CC} = 2.7V$ $V_{CC} = 3.0V$ $V_{CC} = 3.6V$		0.5 0.6 0.5 0.5	V
V _{OH}	HIGH Level Output Voltage	$\begin{array}{l} 2.3V \leq V_{CC} \leq 3.6V; \ I_{OH} = -100 \mu A \\ V_{CC} = 2.3V; \ I_{OH} = -8mA \\ V_{CC} = 2.7V; \ I_{OH} = -12mA \\ V_{CC} = 3.0V; \ I_{OH} = -24mA \end{array}$	V _{CC} - 0.2 1.7 2.1 2.2		V
V _{OL}	LOW Level Output Voltage	$\begin{array}{l} 2.3V \leq V_{CC} \leq 3.6V; \ I_{OL} = 100 \mu A \\ V_{CC} = 2.3V; \ I_{OL} = 8 m A \\ V_{CC} = 2.7V; \ I_{OL} = 12 m A \\ V_{CC} = 3.0V; \ I_{OL} = 24 m A \end{array}$		0.2 0.6 0.6 0.6	V
l _l	Input Leakage Current	$2.3 \text{V} \leq \text{V}_{CC} \leq 3.6 \text{V}; \ 0 \text{V} \leq \text{V}_{I} \leq 5.5 \text{V}$		±5.0	μA
I _{CC}	Quiescent Supply Current	$\begin{array}{c} 2.3 V \leq V_{CC} \leq 3.6 V; \ V_{I} = V_{CC} \ or \ GND \\ 2.3 V \leq V_{CC} \leq 3.6 V; \ 3.6 V \leq V_{I} \leq 5.5 V \end{array}$		10 ±10.0	μA
ΔI_{CC}	Increase in I _{CC} per Input	$2.3V \leq V_{CC} \leq 3.6V, \label{eq:VCC}$ One Input at V_{IH} = V_{CC} –0.6		500	μΑ

2. These values of V_1 are used to test DC electrical characteristics only.

AC ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Waveform		Limits				Unit
				T _A = −40°C to +85°C				
			V _{CC} = 3.0 V to 3.6 V		V _{CC} = 2.7 V	V _{CC} = 2.3	V to 2.7 V	
			C _L = 50 pF		$C_{L} = 50 \text{ pF}$ $C_{L} = 50 \text{ pF}$ $C_{L} = 30 \text{ pF}$		30 pF	
			Min	Max	Max	Min	Max	
t _{PLH} t _{PHL}	Propagation Delay Input to Output	1	1 1	3.8 3.8	4.7 4.7	1 1	6.7 6.7	ns
t _{OSHL} t _{OSLH}	Output-to-Output Skew (Note 3.)			1.0 1.0				ns

 Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}); parameter guaranteed by design.

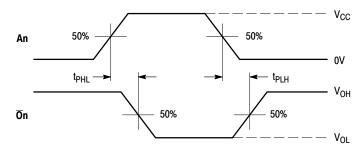
DYNAMIC SWITCHING CHARACTERISTICS

			T _A = +25°C			
Symbol	Characteristic	Condition	Min	Тур	Max	Unit
V _{OLP}	Dynamic LOW Peak Voltage (Note 4.)	V_{CC} = 3.3V, C_{L} = 50pF, V_{IH} = 3.3V, V_{IL} = 0V		0.8		V
V _{OLV}	Dynamic LOW Valley Voltage (Note 4.)	V_{CC} = 3.3V, C_{L} = 50pF, V_{IH} = 3.3V, V_{IL} = 0V		0.8		V

Number of outputs defined as "n". Measured with "n-1" outputs switching from HIGH-to-LOW or LOW-to-HIGH. The remaining output is measured in the LOW state.

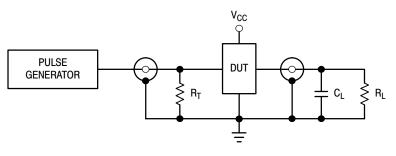
CAPACITIVE CHARACTERISTICS

Symbol	Parameter	Condition	Typical	Unit
C _{IN}	Input Capacitance	V_{CC} = 3.3V, V_{I} = 0V or V_{CC}	7	pF
C _{OUT}	Output Capacitance	V_{CC} = 3.3V, V_{I} = 0V or V_{CC}	8	pF
C _{PD}	Power Dissipation Capacitance	10MHz, V_{CC} = 3.3V, V_{I} = 0V or V_{CC}	25	pF



PROPAGATION DELAYS $t_{R} = t_{F}$ = 2.5ns, 10% to 90%; f = 1MHz; t_{W} = 500ns

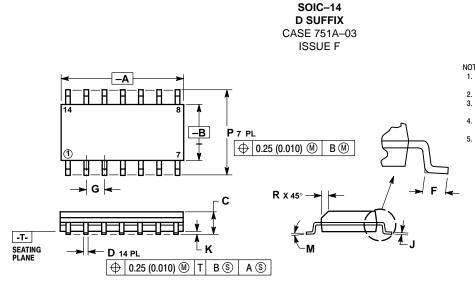
Figure 1. AC Waveforms



 $\begin{array}{l} C_L = 50 p F \mbox{ or equivalent (Includes jig and probe capacitance)} \\ R_L = R_1 = 500 \Omega \mbox{ or equivalent} \\ R_T = Z_{OUT} \mbox{ of pulse generator (typically 50 \Omega)} \end{array}$

Figure 2. Test Circuit

PACKAGE DIMENSIONS

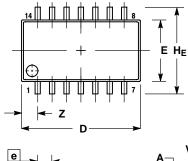


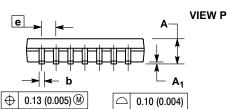
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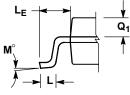
- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- T 14-3M, 1982. CONTROLLING DIMENSION: MILLIMETER. DIMENSIONS A AND B DO NOT INCLUDE MOLD PROTRUSION. MAXIMUM MOLD PROTRUSION 0.15 (0.006)
- PER SIDE. DIMENSION D DOES NOT INCLUDE DAMBAR
- DIMENSION D'DOES NOT INCLODE DAMAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.

	MILLIM	ETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
A	8.55	8.75	0.337	0.344
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.054	0.068
D	0.35	0.49	0.014	0.019
F	0.40	1.25	0.016	0.049
G	1.27	BSC	0.050	BSC
J	0.19	0.25	0.008	0.009
K	0.10	0.25	0.004	0.009
М	0°	7 °	0 °	7 °
Р	5.80	6.20	0.228	0.244
R	0.25	0.50	0.010	0.019

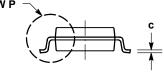












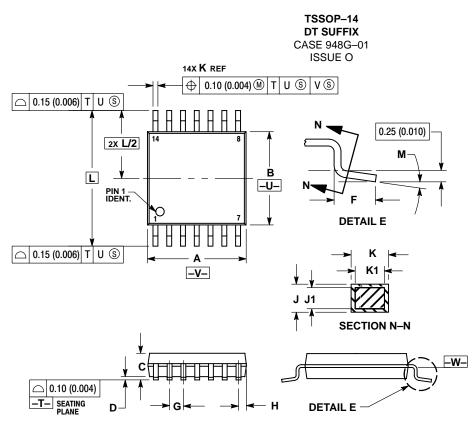
NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: MILLIMETER.
 - DIMENSIONS D AND E DO NOT INICIDET.
 DIMENSIONS D AND E DO NOT INICIDE MOLD FLASH OR PROTRUSIONS AND ARE MEASURED AT THE PARTING LINE. MOLD FLASH OR PROTRUSIONS SHALL NOT EXCEED 0.15 (0.006)

 PHO INUSIONS SHALL NOT EACEED 5.13 (0.000)
 PER SIDE.
 TERMINAL NUMBERS ARE SHOWN FOR REFERENCE ONLY.
 THE LEAD WIDTH DIMENSION (b) DOES NOT INCLUDE DAMBAR PROTRUSION SHALL BE 0.08 (0.003)
 TATATI IN EVCRES OF THE I EAD WIDTH DAIBAR FRO ROSION SHALL BE 0.00 (0.003) TOTAL IN EXCESS OF THE LEAD WIDTH DIMENSION AT MAXIMUM MATERIAL CONDITION. DAMBAR CANNOT BE LOCATED ON THE LOWER RADIUS OR THE FOOT. MINIMUM SPACE BETWEEN PROTRUSIONS AND ADJACENT LEAD TO BE 0.46 (0.018).

	MILLIN	IETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α		2.05		0.081
A ₁	0.05	0.20	0.002	0.008
b	0.35	0.50	0.014	0.020
C	0.18	0.27	0.007	0.011
D	9.90	10.50	0.390	0.413
Е	5.10	5.45	0.201	0.215
е	1.27	BSC	0.050 BSC	
HE	7.40	8.20	0.291	0.323
L	0.50	0.85	0.020	0.033
LE	1.10	1.50	0.043	0.059
Μ	0 °	10 °	0 °	10 °
Q1	0.70	0.90	0.028	0.035
Z		1.42		0.056

PACKAGE DIMENSIONS



NOTES:

- VOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: MILLIMETER. 3. DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0 006) DEP SIDE
- 0R GATE BUHRS STALL NOT EACEED 0.13 (0.006) PER SIDE. 4. DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED
- PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE. 5. DIMENSION K DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION. 6. TERMINAL NUMBERS ARE SHOWN FOR DECEOPENCE ONLY
- REFERENCE ONLY.
 DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-.

	MILLIN	IETERS	INC	HES	
DIM	MIN	MAX	MIN	MAX	
Α	4.90	5.10	0.193	0.200	
В	4.30	4.50	0.169	0.177	
С		1.20		0.047	
D	0.05	0.15	0.002	0.006	
F	0.50	0.75	0.020	0.030	
G	0.65	BSC	0.026 BSC		
Н	0.50	0.60	0.020	0.024	
J	0.09	0.20	0.004	0.008	
J1	0.09	0.16	0.004	0.006	
K	0.19	0.30	0.007	0.012	
K1	0.19	0.25	0.007	0.010	
L	6.40		0.252 BSC		
Μ	0 °	8°	0°	8 °	

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